## AGILENT TECHNOLOGIES, INC. Legal Department, DL429 Intellectual Property Administration P. O. Box 7599 Loveland, Colorado 80537-0599

PATENT APPLICATION

ATTORNEY DOCKET NO. \_\_\_\_\_10031440-1

## IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Inventor(s)	Gregory D. VanWiggeren et al
Serial No.:	Examiner:
Filing Date:	Group Art Unit:
Title:	Optical Phase Measurement Of Target
PO Box 14	VA 22313-1450
<b></b>	INFORMATION DISCLOSURE STATEMENT
Sir:	:
	ormation Disclosure Statement is submitted:
( <b>X</b> )	under 37 CFR 1.97(b), or (Within three months of filing national application; or date of entry of national application; or before mailing date of first office action on the merits; whichever occurs last)
( )	under 37 CFR 1.97(c) together with either a:  ( ) Statement under 37 CFR 1.97(e), or  ( ) a \$180.00 Processing fee under 37 CFR 1.17(p), or  (After the CFR 1.97 (b) time period, but before final action or notice of allowance, whichever occurs first)
	under 37 CFR 1.97 (d) together with a:  ( ) Statement under 37 CFR 1.97(e), and  ( ) a \$180.00 processing fee under 37 CFR 1.17(p).  (Filed after final action or notice of allowance, whichever occurs first, but before payment of the issue fee)
of this applic	ge to Deposit Account <b>50-1078</b> the sum of \$0.00 . At any time during the pendency ration, please charge any fees required or credit any overpayment to Deposit Account ruant to 37 CFR 1.25.
	cant(s) submit herewith Form PTO 1449. References identified with an asterisk (*) were Patent Application No filed, now U. S. Patent No, and, as such, copies thereof are not included pursuant to the provisions of 37 CFR
and other fo individuals(s) attached she foreign paten report or action	ise explanation of the relevance of foreign language patents, foreign language publications reign language information listed on PTO Form 1449, as presently understood by the designated in 37 CFR 1.56 (c) most knowledgeable about the content is given on the et, or where a foreign language patent is cited in a search report or other action by a set office in a counterpart foreign application, an English language version of the search on which indicates the degree of relevance found by the foreign office is listed on form PTO enclosed herewith.
	Deposit March 8, 2004  Respectfully submitted,
I hereby certify t United States F Office to Addres	that this is being deposited with the Postal Service "Express Mail Post see" service under 37 CFR 1:10 on ted above and is addressed to: for Patents, PO Box 1450,

Typed Name: Nelia T. de Guzman

Date: March 8, 2004

Attorney/Agent for Applicant(s)

Telephone No.: (650) 485-5511

Reg. No. 40,026

Rev 05/03 (IDSXML)

Sheet 1 of 4

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<sup>\*</sup>Copies of these references are not enclosed pursuant to 37 CFR 1.98(d). (See accompanying IDS)

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<sup>\*</sup>Copies of these references are not enclosed pursuant to 37 CFR 1.98(d). (See accompanying IDS)

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